Supplementary information

Enhancement of thermoelectric power factor by tuning the carrier concentration in Cu-rich and Ge-poor colusites Cu_{26+x}Nb₂Ge_{6-x}S₃₂

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Temperature dependence of the (a) thermal diffusivity D and (b) heat capacity C_p for the sintered compacts of Cu_{26+x}Nb₂Ge_{6-x}S₃₂ (x = 0, 0.3, 0.5, 0.7).



Rietveld refinement of the XRD pattern of the sintered compact of $Cu_{26}Nb_2Ge_6S_{32}$. The experimental data are marked as red dots. The calculated pattern is in black and the difference between experimental and calculated patterns is shown in blue. The vertical green bars stand for the expected Bragg positions of colusite.



Rietveld refinement of the XRD pattern of the sintered compact of $Cu_{26,3}Nb_2Ge_{5,7}S_{32}$. The experimental data are marked as red dots. The calculated pattern is in black and the difference between experimental and calculated patterns is shown in blue. The vertical green bars stand for the expected Bragg positions of colusite.



Rietveld refinement of the XRD pattern of the sintered compact of $Cu_{26.5}Nb_2Ge_{5.5}S_{32}$. The experimental data are marked as red dots. The calculated pattern is in black and the difference between experimental and calculated patterns is shown in blue. The vertical green bars stand for the expected Bragg positions of colusite.



Rietveld refinement of the XRD pattern of the sintered compact of $Cu_{26.7}Nb_2Ge_{5.3}S_{32}$. The experimental data are marked as red dots. The calculated pattern is in black and the difference between experimental and calculated patterns is shown in blue. The vertical green bars stand for the expected Bragg positions of colusite.



Lattice parameter (a) as a function of additional Cu content x in $Cu_{26+x}Nb_2Ge_{6-x}S_{32}$.



Figure S7

Scanning electron microscopy-secondary electrons images of the fractured surface of the sintered compacts of (a) $Cu_{26}Nb_2Ge_6S_{32}$, (b) $Cu_{26.3}Nb_2Ge_{5.7}S_{32}$, (c) $Cu_{26.5}Nb_2Ge_{5.5}S_{32}$, and (d) $Cu_{26.7}Nb_2Ge_{5.3}S_{32}$.



Scanning electron microscopy-backscattered electron microscopy image and corresponding X-ray maps of the sintered compact of $Cu_{26}Nb_2Ge_6S_{32}$.



Scanning electron microscopy-backscattered electron microscopy image and corresponding X-ray maps of the sintered compact of $Cu_{26.3}Nb_2Ge_{5.7}S_{32}$.



Scanning electron microscopy-backscattered electron microscopy image and corresponding X-ray maps of the sintered compact of $Cu_{26.5}Nb_2Ge_{5.5}S_{32}$.



 $Scanning \ electron\ microscopy-backscattered\ electron\ microscopy\ image\ and\ corresponding\ X-ray\ maps$ of the sintered compact of $Cu_{26.7}Nb_2Ge_{5.3}S_{32}.$



High-resolution transmission electron microscopy (HRTEM) images of the sintered compacts of $Cu_{26}Nb_2Ge_6S_{32}$ and $Cu_{26.5}Nb_2Ge_{5.5}S_{32}$ along the main zone axis (a),(b) [011], and (c),(d) [111], respectively. Electron diffraction patterns of the corresponding HRTEM images are given as insets.



High-angle annular dark-field scanning transmission electron microscopy (HAADF-STEM) image of $Cu_{26}Nb_2Ge_6S_{32}$ along main zone axis [001] is shown in the top panel. The relative intensities between the columns composed of Nb+Cu, Cu+Ge, Cu, and Ge along the lines (a), (b) and (c) are shown in the bottom panel.



High-angle annular dark-field scanning transmission electron microscopy (HAADF-STEM) image of of $Cu_{26.5}Nb_2Ge_{5.5}S_{32}$ along main zone axis [001] is shown in the top panel. The relative intensities between the columns composed of Nb+Cu, Cu+Ge, Cu, and Ge along the lines (a), (b) and (c) are shown in the bottom panel.



Temperature dependence of the estimated Lorenz number *L* for the sintered compacts of $Cu_{26+x}Nb_2Ge_{6-x}S_{32}$ (*x* = 0, 0.3, 0.5, 0.7).

Table S1

Chemical composition of the colusite matrix of the sintered compacts of $Cu_{26+x}Nb_2Ge_{6-x}S_{32}$ (x = 0, 0.3, 0.5, 0.7) determined by energy dispersive X-ray (EDX) spectroscopy of the colusite matrix. The EDX chemical compositions were averaged over fourteen spot measurements of the matrix, and normalized according to two assumptions: (i) the total content for cations (Cu, Nb, and Ge) is 34, which corresponds to the total number of crystallographic sites for cations in the unit cell, and (ii) the content for sulfur is 32. The standard deviation of the mean composition is given in parentheses.

Sample		Chemical composition			
Sample		Cu	Nb	Ge	S
Cu ₂₆ Nb ₂ Ge ₆ S ₃₂	EDX (at.%)	42.2(14)	2.8(2)	9.5(8)	45.4(13)
	(i) Cation = 34	26.3(5)	1.7(1)	5.9(5)	28.4(15)
	(ii) Sulfur = 32	29.8(13)	2.0(1)	6.7(6)	32
	Nominal	26	2	6	32
$Cu_{26.3}Nb_2Ge_{5.7}S_{32}$	EDX (at.%)	42.5(14)	2.8(2)	8.9(8)	45.8(8)
	(i) Cation = 34	26.6(5)	1.8(2)	5.6(5)	28.7(10)
	(ii) Sulfur = 32	29.7(11)	2.0(2)	6.2(6)	32
	Nominal	26.3	2	5.7	32
$Cu_{26.5}Nb_2Ge_{5.5}S_{32}$	EDX (at.%)	42.1(12)	3.3(2)	9.1(5)	45.5(10)
	(i) Cation = 34	26.3(3)	2.1(2)	5.7(3)	28.4(12)
	(ii) Sulfur = 32	29.6(11)	2.3(2)	6.4(4)	32
	Nominal	26.5	2	5.5	32
Cu _{26.7} Nb ₂ Ge _{5.3} S ₃₂	EDX (at.%)	42.4(14)	3.3(2)	8.5(5)	45.8(11)
	(i) Cation = 34	26.6(5)	2.1(2)	5.3(4)	28.6(10)
	(ii) Sulfur = 32	29.6(12)	2.3(2)	5.9(4)	32
	Nominal	26.7	2	5.3	32

Table S2

Measured density d_{meas} and theoretical density d_{theo} of the sintered compacts of $\text{Cu}_{26+x}\text{Nb}_2\text{Ge}_{6-x}\text{S}_{32}$ (x = 0, 0.3, 0.5, 0.7). The d_{theo} was calculated from the estimated lattice parameter a (Table S1 in the Supplementary Information) and nominal chemical composition.

Sample	$d_{\rm meas}$ (g cm ⁻³)	d_{theo} (g cm ⁻³)	
	300 K	300 K	
$Cu_{26}Nb_2Ge_6S_{32}$	4.56	4.49	
$Cu_{26.3}Nb_{2}Ge_{5.7}S_{32}$	4.62	4.47	
$Cu_{26.5}Nb_2Ge_{5.5}S_{32}$	4.70	4.46	
$Cu_{26.7}Nb_{2}Ge_{5.3}S_{32}$	4.71	4.46	